

<b>Notice of References Cited</b>	Application/Control No. 10/530,436	Applicant(s)/Patent Under Reexamination SHEN ET AL.	
	Examiner HEE SOO KIM	Art Unit 2457	Page 1 of 1

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*	B	US-2003/0156108 A1	08-2003	Vetro, Anthony	345/418
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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